## Notice of References Cited

Application/Control No. 10/615,087	Reexamination	Applicant(s)/Patent Under Reexamination PARK, JONG-BUM		
Examiner	Art Unit			
Mary Wilczewski	2822	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,429,087	08-2002	Kwok et al.	438/381
	В	US-6,696,721	02-2004	Hieda, Katsuhiko	257/306
	С	US-2002/0057548	05-2002	CRENSHAW et al.	361/302
	D	US-2002/0168847	11-2002	Narwankar et al.	438/635
	Е	US-6,706,607	03-2004	Park et al.	438/393
	F	US-2004/0005788	01-2004	Gonzalez et al.	438/776
	G	US-2003/0153145	08-2003	Sandhu et al.	438/239
	Н	US-2003/0030093	02-2003	Agarwal et al.	257/306
	l	US-2003/0020138	01-2003	Zheng, Lingyi A.	257/534
	J	US-6,743,672	06-2004	Park, Jong-Bum	438/253
	К	US-2001/0039084	11-2001	Cho et al.	438/238
	L	US-2004/0126982	07-2004	Park, Jong-Bum	438/396
	М	US-2004/0145057	07-2004	Choi, Hyung-Bok	257/758

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.